	Type	Hits	Search Text	DBs	Time Stamp	Comments
1	BRS	2	improv$3 with edge$1 with signal$1 with (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:33	
2	BRS	2	improv$3 with edge$1 with signal$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:33	
3	BRS	18	tim$3 with edge$1 with signal$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:47	
4	BRS	1	tim$3 with edge$1 with signal$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or digital with processing with system$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:01	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
5	BRS	3	tim$3 with edge$1 with signal$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or digital with process$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:02	
6	BRS	8	tim$3 with edge$1 with signal$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:02	
7	BRS	0	tim$3 with edge$1 with signal$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and (calculat$3 or comput$3) with error$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:03	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
8	BRS	5	tim$3 with edge$1 with signal$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and (calculat$3 or comput$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:29	
9	BRS	3	tim$3 with edge$1 with signal$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and calculat$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:30	
10	BRS	3	tim$3 with edge$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and calculat$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:31	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
11	BRS	4	tim$3 with edge$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and error$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:31	
12	BRS	4	tim$3 with edge$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and accurac$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:32	
13	BRS	21	tim$3 with edge$1 same accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:45	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
14	BRS	13	tim$3 with edge$1 with accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:51	
15	BRS	9	tim$3 with edge$1 with accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with signal$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:52	
16	BRS	10	tim$3 with edge$1 with accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:52	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
17	BRS	1	(calibrat$3 or adjust$3) with tim$3 with edge$1 with accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:53	
18	BRS	12	(calibrat$3 or adjust$3) with tim$3 with edge$1 and accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:02	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
19	BRS	4	(calibrat$3 or adjust$3) with tim$3 with edge$1 and accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3 and instruct$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:02	
20	BRS	5	(calibrat$3 or adjust$3) with tim$3 with edge$1 and accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3 and error$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
21	BRS	12	(calibrat$3 or adjust$3) with tim$3 with edge$1 and accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3 and clock$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	
22	BRS	15	(calibrat$3 or adjust$3) with tim$3 with edge$1 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3 and clock$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:04	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
23	BRS	0	(calibrat$3 or adjust$3) with tim$3 with edge$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3 and clock$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:05	
24	BRS	4	(calibrat$3 or adjust$3) with tim$3 with edge$1 same (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3 and clock$1 and (DUT or device$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:07	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
25	BRS	4	(calibrat$3 or adjust$3) with tim$3 with edge$1 same (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3 and clock$1 and (DUT or device$1 adj under adj test) and (reference$1 or threshold$1 or desired or expected or predefined or predetermined or preset$4) with tim$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:07	
26	BRS	4	(calibrat$3 or adjust$3) with tim$3 with edg$3 same (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3 and clock$1 and (DUT or device$1 adj under adj test) and (reference$1 or threshold$1 or desired or expected or predefined or predetermined or preset$4) with tim$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:08	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
27	BRS	28	(calibrat$3 or adjust$3) with tim$3 with edg$3 and test$3 with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3 and clock$1 and (DUT or device$1 adj under adj test) and (reference$1 or threshold$1 or desired or expected or predefined or predetermined or preset$4) with tim$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:08	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
28	BRS	20	(calibrat$3 or adjust$3) with tim$3 with edg$3 and test$3 with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3 and clock$1 and (DUT or device$1 adj under adj test) and (reference$1 or threshold$1 or desired or expected or predefined or predetermined or preset$4) with tim$3 and computer$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:09	
29	BRS	9747	702/57,69.ccls. or 714/724,742,744.ccls. or 324/158.1.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:10	
30	BRS	2	improv$3 with edge$1 with signal$1 with (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:33	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
31	BRS	2	improv$3 with edge$1 with signal$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:33	
32	BRS	19	tim$3 with edge$1 with signal$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:49	
33	BRS	2	(expected or desired) with tim$3 with edge$1 with signal$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:49	
34	BRS	2	"20060036387"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:58	
35	BRS	1	tim$3 with edge$1 with signal$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or digital with processing with system$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:01	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
36	BRS	3	tim$3 with edge$1 with signal$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or digital with process$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:02	
37	BRS	8	tim$3 with edge$1 with signal$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:02	
38	BRS	0	tim$3 with edge$1 with signal$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and (calculat$3 or comput$3) with error$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:11	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
39	BRS	2	(compar$4 or differen$2) with tim$3 with edge$1 with signal$1 with (threshold$1 or reference$1 or expected or desired or predetermined or preset$4 or predefined) and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and (calculat$3 or comput$3) with error$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:15	
40	BRS	1	tim$3 with edge$1 with signal$1 with (threshold$1 or reference$1 or expected or desired or predetermined or preset$4 or predefined) same (DUT or device$1 adj under adj test) with (DPS or (data or digit$2) with process$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:17	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
41	BRS	26	tim$3 with edge$1 with signal$1 with (threshold$1 or reference$1 or expected or desired or predetermined or preset$4 or predefined) same (DUT or device$1 adj under adj test) and (DPS or (data or digits$2) with process$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:20	
42	BRS	1	tim$3 with occurrence$1 with edge$1 with signal$1 with (DUT or device$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:21	
43	BRS	8	(threshold$1 or reference$1 or expected or desired or predetermined or preset$4 or predefined) with tim$3 with point$1 with edge$1 with signal$1 same (DUT or device$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:26	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
44	BRS	39	(threshold$1 or reference$1 or expected or desired or predetermined or preset$4 or predefined) with tim$3 with point$1 with edge$1 with signal$1 and (DUT or device$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:27	
45	BRS	2	(determin$3 or calculat$3 or computing or comput or computa) with (threshold$1 or reference$1 or expected or desired or predetermined or preset$4 or predefined) with tim$3 with point$1 with edge$1 with signal$1 and (DUT or device$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:27	
46	BRS	5	tim$3 with edge$1 with signal$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and (calculat$3 or comput$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:29	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
47	BRS	3	tim$3 with edge$1 with signal$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and calculat$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:30	
48	BRS	3	tim$3 with edge$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and calculat$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:31	
49	BRS	4	tim$3 with edge$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and error$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:31	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
50	BRS	4	tim$3 with edge$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and accurac$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:32	
51	BRS	23	tim$3 with edge$1 same accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:46	
52	BRS	40	tim$3 with edge$1 same occur$6 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:49	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
53	BRS	24	tim$3 with edge$1 with occur$6 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:50	
54	BRS	0	compar$4 with tim$3 with edge$1 with occur$6 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:50	
55	BRS	4	compar$4 same tim$3 with edge$1 with occur$6 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:50	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
56	BRS	14	tim$3 with edge$1 with accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:51	
57	BRS	10	tim$3 with edge$1 with accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with signal$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:52	
58	BRS	11	tim$3 with edge$1 with accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:52	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
59	BRS	2	(calibrat$3 or adjust$3) with tim$3 with edge$1 with accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:58	
60	BRS	2	(calibrat$3 or adjust$3 or compensat$3) with tim$3 with edge$1 with accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:59	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
61	BRS	13	(calibrat$3 or adjust$3) with tim$3 with edge$1 and accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:02	
62	BRS	5	(calibrat$3 or adjust$3) with tim$3 with edge$1 and accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3 and instruct$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
63	BRS	13	(calibrat$3 or adjust$3 or compensat$3) with tim$3 with edge$1 and accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:02	
64	BRS	5	(calibrat$3 or adjust$3 or compensat$3) with tim$3 with edge$1 and accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3 and instruct$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
65	BRS	6	(calibrat$3 or adjust$3) with tim$3 with edge$1 and accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3 and error$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	
66	BRS	6	(calibrat$3 or adjust$3 or compensat$3) with tim$3 with edge$1 and accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3 and error$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
67	BRS	13	(calibrat$3 or adjust$3) with tim$3 with edge$1 and accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3 and clock$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	
68	BRS	13	(calibrat$3 or adjust$3 or compensat$3) with tim$3 with edge$1 and accurac$3 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) or digit$2) with process$3) and cycle$1 with tim$3 and clock$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:04	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
69	BRS	17	(calibrat$3 or adjust$3 or compensat$3) with tim$3 with edge$1 and (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3 and clock$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:04	
70	BRS	0	(calibrat$3 or adjust$3) with tim$3 with edge$1 same (DUT or device$1 adj under adj test) with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3 and clock$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:07	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
71	BRS	5	(calibrat$3 or adjust$3 or compensat$3) with tim$3 with edge$1 same (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3 and clock$1 and (DUT or device$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:07	
72	BRS	5	(calibrat$3 or adjust$3 or compensat$3) with tim$3 with edge$1 same (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3 and clock$1 and (DUT or device$1 adj under adj test) and (reference$1 or threshold$1 or desired or expected or predefined or predetermined or preset$4) with tim$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:07	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
73	BRS	5	(calibrat$3 or adjust$3 or compensat$3) with tim$3 with edg$3 same (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3 and clock$1 and (DUT or device$1 adj under adj test) and (reference$1 or threshold$1 or desired or expected or predefined or predetermined or preset$4) with tim$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:08	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
74	BRS	32	(calibrat$3 or adjust$3 or compensat$3) with tim$3 with edg$3 and test$3 with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3 and clock$1 and (DUT or device$1 adj under adj test) and (reference$1 or threshold$1 or desired or expected or predefined or predetermined or preset$4) with tim$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:09	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
75	BRS	24	(calibrat$3 or adjust$3 or compensat$3) with tim$3 with edg$3 and test$3 with (integrated adj circuit$1 or IC$1) and (DPS or (data or digit$2) with process$3) and cycle$1 with tim$3 and clock$1 and (DUT or device$1 adj under adj test) and (reference$1 or threshold$1 or desired or expected or predefined or predetermined or preset$4) with tim$3 and computer$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:09	
76	BRS	18	(702/57,69.ccls. or 714/724,742,744.ccls. or 324/158.1.ccls.) and tim$3 with point$1 with edge$1 with signal$1 and (DUT or device$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:18	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
77	BRS	6	(702/57,69.ccls. or 714/724,742,744.ccls. or 324/158.1.ccls.) and tim$3 with point$1 with edge$1 with signal$1 same (DUT or device$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:13	
78	BRS	2	(702/57,69.ccls. or 714/724,742,744.ccls. or 324/158.1.ccls.) and tim$3 with point$1 with edge$1 with signal$1 with (DUT or device$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:13	
79	BRS	112	tim$3 with point$1 with edge$1 with signal$1 and (DUT or device$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:17	
80	BRS	23	(702/57,69,117.ccls. or 714/724,742,744.ccls. or 324/158.1.ccls.) and tim$3 with point$1 with edge$1 with signal$1 and (DUT or device$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:24	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
81	BRS	86	("702"/$.ccls. or "714"/$.ccls. or "324"/$.ccls.) and tim$3 with point$1 with edge$1 with signal$1 and (DUT or device$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:19	
82	BRS	42	(702/57,69,117,119.ccls. or 714/700,718,724,736,742,743,744,815.ccls. or 324/158.1.ccls.) and tim$3 with point$1 with edge$1 with signal$1 and (DUT or device$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:25	
83	BRS	243	(702/57,69,117,119.ccls. or 714/700,718,724,736,742,743,744,815.ccls. or 324/158.1.ccls.) and tim$3 with edge$1 with signal$1 and (DUT or device$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:31	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
84	BRS	116	(702/57,69,117,119.ccls. or 714/700,718,724,736,742,74 3,744,815.ccls. or 324/158.1.ccls.) and tim$3 with edge$1 with signal$1 same (DUT or device$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:25	
85	BRS	53	(702/57,69,117,119.ccls. or 714/700,718,724,736,742,74 3,744,815.ccls. or 324/158.1.ccls.) and tim$3 with edge$1 with signal$1 with (DUT or device$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:27	
86	BRS	9	(702/57,69,117,119.ccls. or 714/700,718,724,736,742,74 3,744,815.ccls. or 324/158.1.ccls.) and tim$3 with edge$1 with signal$1 with (DUT or device$1 adj under adj test)	US-PGPUB	2006/03/27 11:29	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
87	BRS	12	(count$3 or occur$6 or number$1) with tim$3 with edge$1 with signal$1 with (DUT or device$1 adj under adj test)	US-PGPUB	2006/03/27 12:28	
88	BRS	4	(compar$4 or differen$2) with (count$3 or occur$6 or number$1) with tim$3 with edge$1 with signal$1 with (DUT or device$1 adj under adj test)	US-PGPUB	2006/03/27 11:30	
89	BRS	43	(702/57,69,117,119.ccls. or 714/700,718,724,736,742,743,744,815.ccls. or 324/158.1.ccls.) and tim$3 with edge$1 with signal$1 and (DUT or device$1 adj under adj test)	US-PGPUB	2006/03/27 11:31	
90	BRS	170	cycle$ with signal$1 with tester$1 with cycle$1 with tim$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:46	
91	BRS	70	generat$3 with cycle$ with signal$1 with tester$1 with cycle$1 with tim$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:47	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
92	BRS	6	generat$3 with cycle$ with edge with signal$1 with tester$1 with cycle$1 with tim$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:49	
93	BRS	7	generat$3 with cycle$ with edge with signal$1 with ((DUT or device adj under adj test$3) or tester$1) with cycle$1 with tim$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:50	
94	BRS	12	(count$3 or occur$6 or number$1) with tim$3 with (peak$1 or edge$1) with signal$1 with (DUT or device$1 adj under adj test)	US-PGPUB	2006/03/27 12:28	
95	BRS	0	compar44 with expected with tim$3 with edge with signal$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 12:55	
96	BRS	40	compar$4 with expected with tim$3 with edge with signal$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 12:55	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
97	BRS	2	compar$4 with expected with tim$3 with edge with signal$1 same (DUT or device$1 adj under adj test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 12:56	
98	BRS	2	compar$4 with (desired or expected) with tim$3 with edge with signal$1 same (DUT or device$1 adj under adj test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 12:56	
99	BRS	2	(differen$2 or compar$4) with (desired or expected) with tim$3 with edge with signal$1 same (DUT or device$1 adj under adj test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 12:56	
100	BRS	10	(differen$2 or compar$4) with (desired or expected) with tim$3 with edge$1 with signal$1 and (DUT or device$1 adj under adj test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:08	
101	BRS	126	tim$3 with edge$1 with signal$1 with (DUT or device$1 adj under adj test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:08	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
102	BRS	14	(adjust$3 or calibrat$3 or compensat$3) with tim$3 with edge$1 with signal$1 with (DUT or device$1 adj under adj test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:14	
103	BRS	0	(adjust$3 or calibrat$3 or compensat$3) with tim$3 with edge$1 with signal$1 with actual same (DUT or device$1 adj under adj test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:15	
104	BRS	0	(adjust$3 or calibrat$3 or compensat$3) with (tim$3 adj edge$1) with signal$1 with ((expected or desired) adj tim$3) same (DUT or device$1 adj under adj test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:16	
105	BRS	0	(adjust$3 or calibrat$3 or compensat$3) with (tim$3 adj edge$1) with signal$1 with (expected or desired) same (DUT or device$1 adj under adj test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:16	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
106	BRS	1	(adjust$3 or calibrat$3 or compensat$3) with (tim$3 adj edge$1) with signal$1 with (expected or desired) and (DUT or device$1 adj under adj test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:17	
107	BRS	6	(adjust$3 or calibrat$3 or compensat$3) with (tim$3 adj edge$1) with signal$1 with (expected or desired or predefined or predetermined or preset$4 or reference$1 or threshold$1) and (DUT or device$1 adj under adj test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:21	
108	BRS	12	(adjust$3 or calibrat$3 or compensat$3) with (tim$3 adj edge$1) with signal$1 and (expected or desired or predefined or predetermined or preset$4 or reference$1 or threshold$1) with tim$3 with edge$1 and (DUT or device$1 adj under adj test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:23	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
109	BRS	9	(adjust$3 or calibrat$3 or compensat$3) with (tim$3 adj edge$1) with signal$1 and (expected or desired or predefined or predetermined or preset$4 or reference$1 or threshold$1) with tim$3 with edge$1 and cycle$1 with tim$3 and (DUT or device$1 adj under adj test$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 14:31	
110	BRS	3	(adjust$3 or calibrat$3 or compensat$3) with (tim$3 adj edge$1) with signal$1 and (tester$1 or DUT or (device$1 adj under adj test$3)) with cycle$1 with time$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 14:33	

	U	1	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval Classif
1			US 2006004982 0 A1	20060309	17	Method and apparatus for remotely buffering test channels	324/158.1		324/158. 1
2	X		US 2006003172 8 A1	20060209	15	Method and apparatus for measuring digital timing paths by setting a scan mode of sequential storage elements	714/724		714/724
3	X		US 2006001035 8 A1	20060112	21	Method and apparatus for calibrating and/or deskewing communications channels	714/700	455/67.16	714/700
4	X		US 2005026769 6 A1	20051201		Measurement instrument and measurement method	702/57		702/57
5	X		US 2005024660 3 A1	20051103	12	Pin coupler for an integrated circuit tester	714/742		714/742
6	X		US 2005024660 1 A1	20051103		Method and apparatus to measure and display data dependent eye diagrams	714/724		714/724

	U	1	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval Classif
7	X		US 20050225314 A1	20051013		Method of measuring duty cycle	324/158.1		324/158.1
8	X		US 20050193355 A1	20050901	19	Source synchronous timing extraction, cyclization and sampling	716/6	703/19; 714/724	714/724
9	X		US 20050160331 A1	20050721		PICA system timing measurement and calibration	714/700		714/700
10	X	X	US 20050097420 A1	20050505	26	Apparatus for jitter testing an IC	714/742		714/742
11	X		US 20050088167 A1	20050428		Isolation buffers with controlled equal time delays	324/158.1		324/158.1
12	X		US 20050080580 A1	20050414	27	Device for testing lsi to be measured, jitter analyzer, and phase difference detector	702/117		702/117
13	X		US 20050050411 A1	20050303		Pre-stored digital word generator	714/724		714/724

	U	1	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval Classif
14	X		US 20050038615 A1	20050217		Qualification signal measurement, trigger, and/or display system	702/69		702/69
15	X		US 20050034044 A1	20050210	25	Semiconductor test device and timing measurement method	714/742		714/742
16	X		US 20050028062 A1	20050203		Test method and apparatus for high-speed semiconductor memory devices	714/736		714/736
17	X		US 20050022208 A1	20050127		Semiconductor tester	714/744		714/744
18	X		US 20050022201 A1	20050127	42	Test systems and methods with compensation techniques	714/724		714/724
19	X		US 20050022200 A1	20050127	43	Systems and methods associated with test equipment	714/724		714/724
20	X		US 20040260492 A1	20041223	9	Direct jitter analysis of binary sampled data	702/69		702/69

	U 1	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval Classif
21	X	US 20040153267 A1	20040805		System and method of testing a transceiver	702/69		702/69
22	X	US 20040122607 A1	20040624		System and method of measuring a signal propagation delay	702/69		702/69
23	X	US 20040078740 A1	20040422		Memory tester uses arbitrary dynamic mappings to serialize vectors into transmitted sub-vectors and de-serialize received sub-vectors into vectors	714/718		714/718
24	X	US 20040064765 A1	20040401		Deskewed differential detector employing analog-to-digital converter	714/700	714/724	714/700; 714/724
25	X	US 20040051518 A1	20040318		High speed tester with narrow output pulses	324/158.1		324/158.1
26	X	US 20040000332 A1	20040101		Instrument initiated communication for automatic test equipment	714/724		714/724

	U	1	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval Classif
27	X		US 2003023360 4 A1	20031218		Memory device test system and method	714/718		714/718
28	X		US 2003022946 6 A1	20031211		Test method and apparatus for source synchronous signals	702/117		702/117
29	X		US 2003015868 7 A1	20030821	11	Composite eye diagrams	702/117		702/117
30	X		US 2003012653 0 A1	20030703	13	Time shift circuit for functional and AC parametric test	714/724		714/724
31	X		US 2003011712 9 A1	20030627	7	Low-cost tester interface module	324/158.1	324/765	324/158.1
32	X		US 2003011042 7 A1	20030612		Semiconductor test system storing pin calibration data in non-volatile memory	714/724		714/724
33	X	X	US 2003002883 2 A1	20030206	18	Driver for integrated circuit chip tester	714/700		714/700
34	X		US 2003000537 5 A1	20030102		Algorithmically programmable memory tester with test sites operating in a slave mode	714/724		714/724

	U	1	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval Classif
35	X		US 20020186004 A1	20021212		Method for manufacturing smart card and identification devices and the like	324/158.1		324/158.1
36	X		US 20020184581 A1	20021205		Method for testing semiconductor chips and semiconductor device	714/724		714/724
37	X		US 20020170006 A1	20021114	17	Differential receiver architecture	714/724		714/724
38	X		US 20020152437 A1	20021017	9	Circuitry for and system and substrate with circuitry for aligning output signals in massively parallel testers and other electronic devices	714/724		714/724
39	X	X	US 20020135357 A1	20020926	14	Method and apparatus for socket calibration of integrated circuit testers	324/158.1		324/158.1

	U	1	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval Classif
40	X		US 2002012587 8 A1	20020912		High-frequency tester for semiconductor devices	324/158.1		324/158. 1
41	X		US 2002007776 3 A1	20020620		Automatic tester having separate coarse and precise timing modules	702/120	702/117	702/117
42	X		US 2002004289 8 A1	20020411		Test interface for verification of high speed embedded synchronous dynamic random access memory (SDRAM) circuitry	714/744	365/192	714/744
43	X		US 2001001046 2 A1	20010802		Carrier identification system, carrier identification method and storage media	324/158.1		324/158. 1

3/27/06, EAST Version: 2.0.3.0